

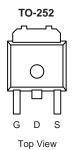
SW2N70D-VB TO252 Datasheet **Power MOSFET**

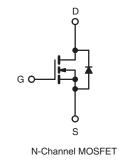
PRODUCT SUMMARY					
V _{DS} (V)	700				
R _{DS(on)} (Ω)	$V_{GS} = 10 V$	6.5			
Q _g (Max.) (nC)	38				
Q _{gs} (nC)	5.0				
Q _{gd} (nC)	21				
Configuration	Single				

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC







ABSOLUTE MAXIMUM RATINGS (T C	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	800	- V	
Gate-Source Voltage			V _{GS}	± 20		
Continuous Drain Current	$T_{\rm C} =$	T _C = 25 °C	- I _D	2.0		
	V _{GS} at 10 V	$T_C = 100 \ ^\circ C$		1.4	А	
Pulsed Drain Current ^a			I _{DM}	7.2		
Linear Derating Factor				0.43	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	180	mJ	
Repetitive Avalanche Current ^a			I _{AR}	2.0	А	
Repetitive Avalanche Energy ^a			E _{AR}	5.4	mJ	
Maximum Power Dissipation	mum Power Dissipation $T_{C} = 25 \text{ °C}$			54	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	*0	
Soldering Recommendations (Peak Temperature) for 10 s			300 ^d	- °C		
Manuatina Tanana	0.00 ar	0.00		10	lbf ∙ in	
Mounting Torque	6-32 or M3 screw			1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 104 mH, $R_g = 25 \Omega$, $I_{AS} = 1.8 \text{ A}$ (see fig. 12). c. $I_{SD} \le 1.8 \text{ A}$, dl/dt $\le 80 \text{ A/}\mu$ s, $V_{DD} \le 600$, $T_J \le 150 \text{ °C}$.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.3		

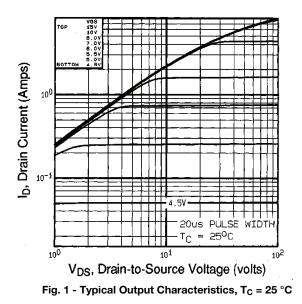
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$) V, I _D = 250 μA	700	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference t	to 25 °C, I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V	′ _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _G	$V_{GS} = \pm 20 \text{ V}$		-	± 100	nA
		V _{DS} = 700 V, V _{GS} = 0 V		-	-	100	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 560 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 125 \text{ °C}$		-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	$V_{GS} = 10 V$	I _D = 1.1 A ^b	-	6.5	-	Ω
Forward Transconductance	g fs	V _{DS} = 10	00 V, I _D = 1.1 A ^b	0.80	-	-	S
Dynamic							
Input Capacitance	C _{iss}	V	ν _{GS} = 0 V,	-	530	-	pF
Output Capacitance	C _{oss}	V	$p_{05} = 25 V$,	-	150	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0	MHz, see fig. 5	-	90	-	
Total Gate Charge	Qg				-	38	
Gate-Source Charge	Q_gs	$V_{GS} = 10 V$	$I_D = 1.8 \text{ A}, V_{DS} = 350 \text{ V},$ see fig. 6 and 13^{b}	-	-	5.0	nC
Gate-Drain Charge	Q _{gd}			-	-	21	
Turn-On Delay Time	t _{d(on)}	V_{DD} = 350 V, I _D = 1.8 A, R _g = 18 Ω , R _D = 230 Ω , see fig. 10 ^b		-	8.2	-	ns
Rise Time	t _r			-	17	-	
Turn-Off Delay Time	t _{d(off)}			-	58	-	
Fall Time	t _f			-	27	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L _S			-	7.5	-	nH
Drain-Source Body Diode Characteristic	S						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	1.8	А
Pulsed Diode Forward Current ^a	I _{SM}			-	-	7.2	
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 1.8 A, V _{GS} = 0 V ^b		-	-	1.4	V
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 1.8 A, dl/dt = 100 A/µs ^b		-	380	570	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.94	1.4	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)				L _D)	

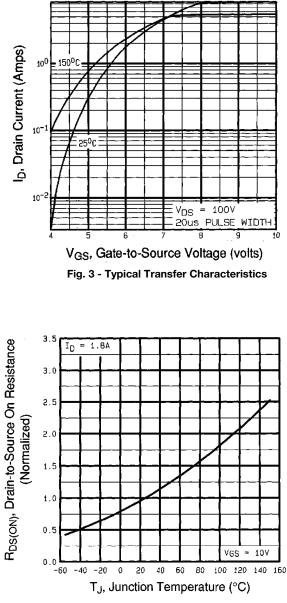
Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.









 V_{DS} , Drain-to-Source Voltage (volts) Fig. 2 - Typical Output Characteristics, T_C = 150 °C

10¹

ΤС

102

20us PULSE WIDT

150⁰C

Fig. 4 - Normalized On-Resistance vs. Temperature

ID, Drain Current (Amps)

100

10

100



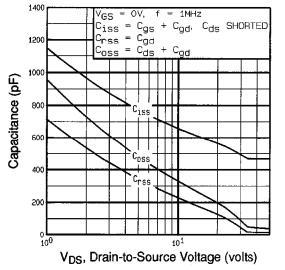


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

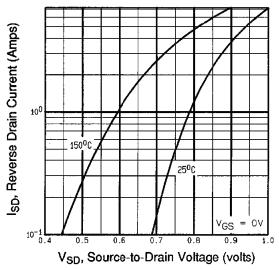


Fig. 7 - Typical Source-Drain Diode Forward Voltage

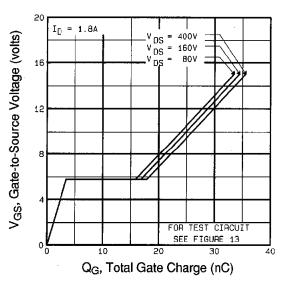
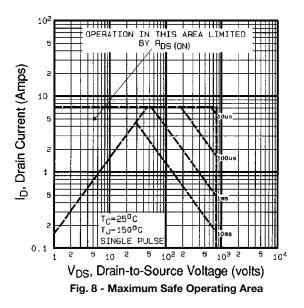


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage





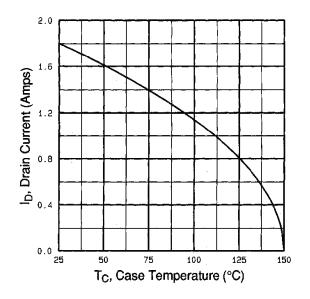


Fig. 9 - Maximum Drain Current vs. Case Temperature

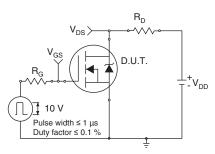


Fig. 10a - Switching Time Test Circuit

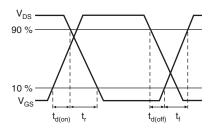


Fig. 10b - Switching Time Waveforms

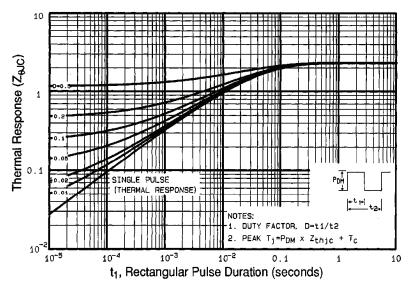


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

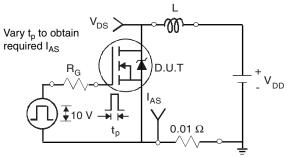
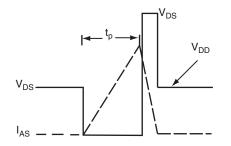


Fig. 12a - Unclamped Inductive Test Circuit



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Fig. 12b - Unclamped Inductive Waveforms

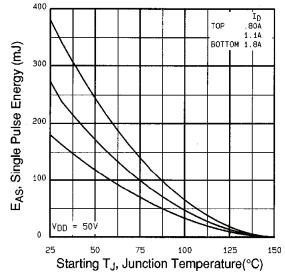


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

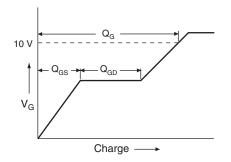


Fig. 13a - Basic Gate Charge Waveform

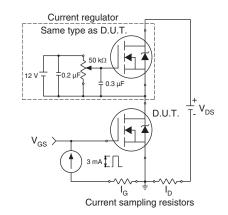
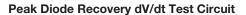
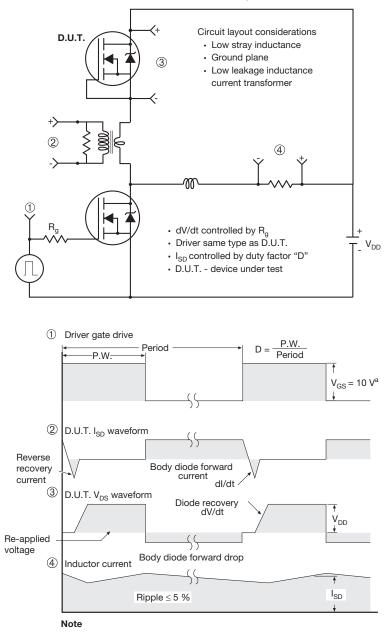


Fig. 13b - Gate Charge Test Circuit



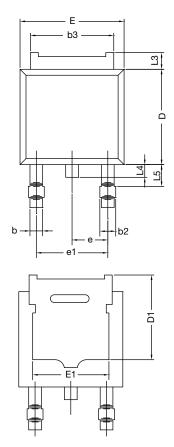




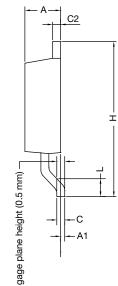
a. $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel





TO-252AA Case Outline



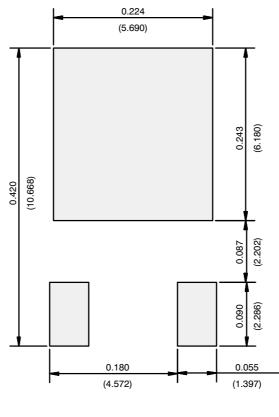
	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
А	2.18	2.38	0.086	0.094	
A1	-	0.127	-	0.005	
b	0.64	0.88	0.025	0.035	
b2	0.76	1.14	0.030	0.045	
b3	4.95	5.46	0.195	0.215	
С	0.46	0.61	0.018	0.024	
C2	0.46	0.89	0.018	0.035	
D	5.97	6.22	0.235	0.245	
D1	4.10	-	0.161	-	
E	6.35	6.73	0.250	0.265	
E1	4.32	-	0.170	-	
Н	9.40	10.41	0.370	0.410	
е	2.28	BSC	0.090 BSC		
e1	4.56 BSC		0.180	0.180 BSC	
L	1.40	1.78	0.055	0.070	
L3	0.89	1.27	0.035	0.050	
L4	-	1.02	-	0.040	
L5	1.01	1.52	0.040	0.060	
ECN: T16-0236-Rev. P, 16-May-16 DWG: 5347					

Notes

• Dimension L3 is for reference only.



RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)



Recommended Minimum Pads Dimensions in Inches/(mm)



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